

# STP4NB100 STP4NB100FP

# N - CHANNEL 1000V - $4\Omega$ - 3.8A - TO-220/TO-220FP PowerMESHTM MOSFET

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	Ι <sub>D</sub>
STP4NB100	1000 V	< 4.4 Ω	3.8 A
STP4NB100FP	1000 V	< 4.4 Ω	3.8 A

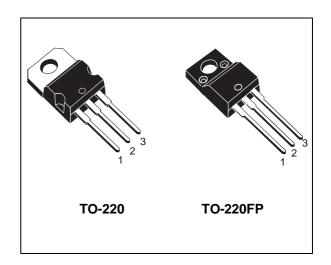
- TYPICAL R<sub>DS(on)</sub> = 4 Ω
- EXTREMELY HIGH dv/dt CAPABILITY
- 100% AVALANCHE TESTED
- VERY LOW INTRINSIC CAPACITANCES
- GATE CHARGE MINIMIZED

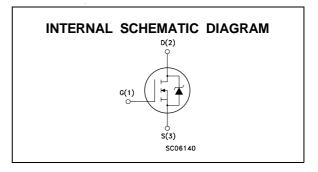
#### **DESCRIPTION**

Using the latest high voltage MESH OVERLAY<sup>TM</sup> process, STMicroelectronics has designed an advanced family of power MOSFETs with outstanding performances. The new patent pending strip layout coupled with the Company's proprietary edge termination structure, gives the lowest RDS(on) per area, exceptional avalanche and dv/dt capabilities and unrivalled gate charge and switching characteristics.

#### **APPLICATIONS**

- HIGH CURRENT, HIGH SPEED SWITCHING
- SWITCH MODE POWER SUPPLIES (SMPS)
- DC-AC CONVERTERS FOR WELDING EQUIPMENT AND UNINTERRUPTIBLE POWER SUPPLIES AND MOTOR DRIVE





#### **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Va	lue	Unit
		STP4NB100	STP4NB100FP	
V <sub>DS</sub>	Drain-source Voltage (V <sub>GS</sub> = 0)	10	000	V
$V_{DGR}$	Drain- gate Voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	10	000	V
$V_{GS}$	Gate-source Voltage	±	30	V
ΙD	Drain Current (continuous) at T <sub>c</sub> = 25 °C	3.8	3.8(*)	Α
I <sub>D</sub>	Drain Current (continuous) at T <sub>c</sub> = 100 °C	2.4	2.4(*)	Α
I <sub>DM</sub> (•)	Drain Current (pulsed)	15.2	15.2	Α
$P_{tot}$	Total Dissipation at T <sub>c</sub> = 25 °C	125	40	W
	Derating Factor	1	0.32	W/°C
dv/dt(1)	Peak Diode Recovery voltage slope	4	4	V/ns
V <sub>ISO</sub>	Insulation Withstand Voltage (DC)	_		
T <sub>stg</sub>	Storage Temperature	-65 t	o 150	°C
T <sub>i</sub>	Max. Operating Junction Temperature	1	150	

<sup>(•)</sup> Pulse width limited by safe operating area

(1)  $I_{SD} \le 3.8A$ ,  $di/dt \le 200 \text{ A/}\mu\text{s}$ ,  $V_{DD} \le V_{(BR)DSS}$ ,  $Tj \le T_{JMAX}$ 

October 1999 1/9

<sup>(\*)</sup> Limited only by maximum temperature allowed

### STP4NB100/STP4NB100FP

#### THERMAL DATA

			TO-220	TO-220FP	
R <sub>thj-case</sub>	Thermal Resistance Junction-case	Max	1	3.12	°C/W
R <sub>thj-amb</sub> R <sub>thc-sink</sub> T <sub>I</sub>	Thermal Resistance Junction-ambient Thermal Resistance Case-sink Maximum Lead Temperature For Soldering F	Max Typ Purpose	62 0. 30	.5	°C/W °C/W °C

#### **AVALANCHE CHARACTERISTICS**

Symbol	Parameter	Max Value	Unit
I <sub>AR</sub>	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T <sub>j</sub> max)	3.8	А
E <sub>AS</sub>	Single Pulse Avalanche Energy (starting $T_i = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	360	mJ

# **ELECTRICAL CHARACTERISTICS** ( $T_{case} = 25$ $^{o}C$ unless otherwise specified) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A$ $V_{GS} = 0$	1000			٧
I <sub>DSS</sub>	Zero Gate Voltage Drain Current (V <sub>GS</sub> = 0)	$V_{DS} = Max Rating$ $V_{DS} = Max Rating$ $T_c = 125  ^{\circ}C$			1 50	μA μA
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 30 V			± 100	nA

### ON (\*)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ $I_D = 250 \mu A$	3	4	5	V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	$V_{GS} = 10 \text{ V}$ $I_D = 2 \text{ A}$		4	4.4	Ω
I <sub>D(on)</sub>	On State Drain Current	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $V_{GS} = 10 \text{ V}$	3.8			Α

#### **DYNAMIC**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> (*)	Forward Transconductance	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $I_D = 2 A$	1.5	3		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V <sub>DS</sub> = 25 V f = 1 MHz V <sub>GS</sub> = 0		1400 117 7		pF pF pF

#### **ELECTRICAL CHARACTERISTICS** (continued)

#### **SWITCHING ON**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub>	Turn-on Time Rise Time	$\begin{split} V_{DD} &= 500 \text{ V} & I_D = 2 \text{ A} \\ R_G &= 4.7 \Omega & V_{GS} = 10 \text{ V} \\ \text{(see test circuit, figure 3)} \end{split}$		20 9		ns ns
$egin{array}{c} Q_g \ Q_{gs} \ Q_{gd} \end{array}$	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 800 \text{ V}$ $I_{D} = 4 \text{ A}$ $V_{GS} = 10 \text{ V}$		32 12 11	45	nC nC nC

#### **SWITCHING OFF**

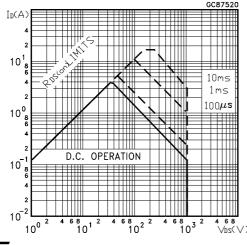
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
$t_{r(Voff)}$	Off-voltage Rise Time	$V_{DD} = 800 \text{ V}  I_{D} = 4 \text{ A}$		15		ns
t <sub>f</sub>	Fall Time	$R_G = 4.7 \Omega V_{GS} = 10 V$		12		ns
t <sub>c</sub>	Cross-over Time	(see test circuit, figure 5)		20		ns

#### SOURCE DRAIN DIODE

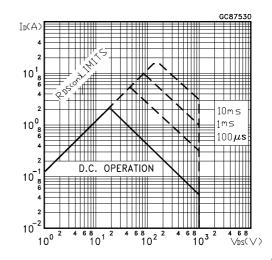
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub> (•)	Source-drain Current Source-drain Current (pulsed)				3.8 15.2	A A
V <sub>SD</sub> (*)	Forward On Voltage	I <sub>SD</sub> = 3.8 A V <sub>GS</sub> = 0			1.6	V
t <sub>rr</sub>	Reverse Recovery Time	$I_{SD} = 4 \text{ A}$ di/dt = 100 A/ $\mu$ s $V_{DD} = 100 \text{ V}$ $T_i = 150 \text{ °C}$		750		ns
$Q_{rr}$	Reverse Recovery Charge	(see test circuit, figure 5)		5.4		μC
$I_{RRM}$	Reverse Recovery Current			14.5		Α

<sup>(\*)</sup> Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %

#### Safe Operating Area for TO-220



#### Safe Operating Area for TO-220FP

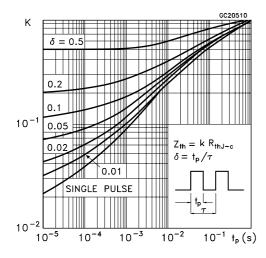


477

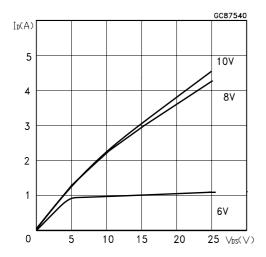
<sup>(•)</sup> Pulse width limited by safe operating area

#### STP4NB100/STP4NB100FP

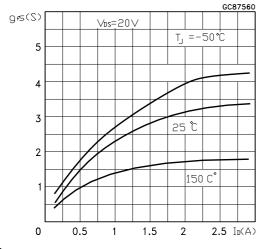
#### Thermal Impedance for TO-220



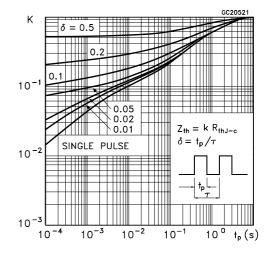
#### **Output Characteristics**



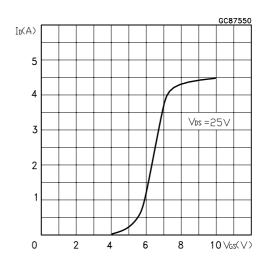
#### Transconductance



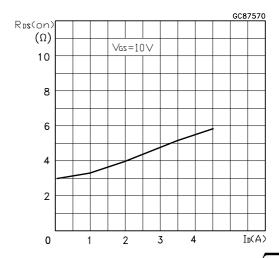
#### Thermal Impedance for TO-220FP



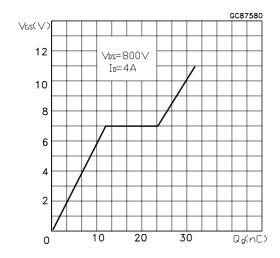
#### **Transfer Characteristics**



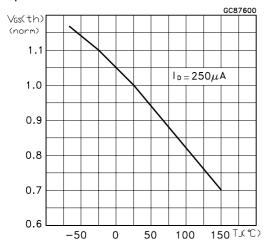
#### Static Drain-source On Resistance



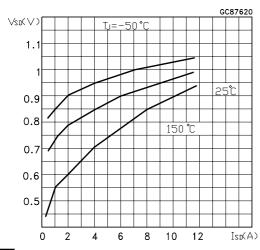
#### Gate Charge vs Gate-source Voltage



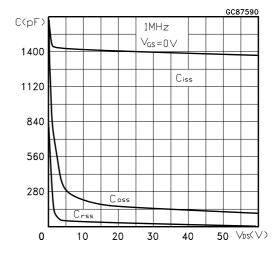
# Normalized Gate Threshold Voltage vs Temperature



#### Source-drain Diode Forward Characteristics



#### Capacitance Variations



#### Normalized On Resistance vs Temperature

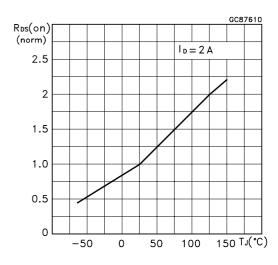
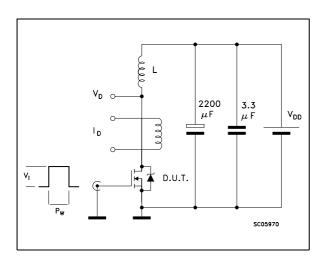
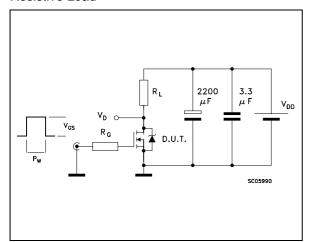


Fig. 1: Unclamped Inductive Load Test Circuit



**Fig. 3:** Switching Times Test Circuits For Resistive Load



**Fig. 5:** Test Circuit For Inductive Load Switching And Diode Recovery Times

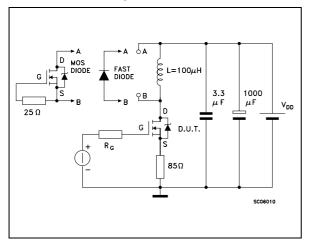


Fig. 2: Unclamped Inductive Waveform

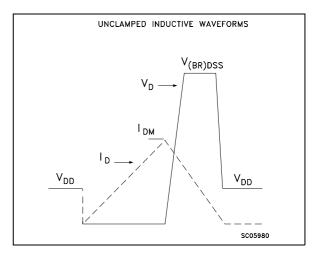
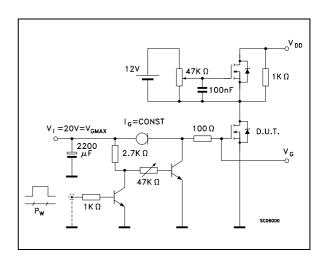
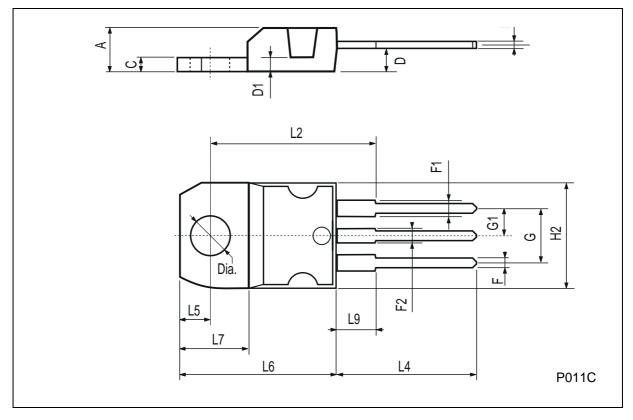


Fig. 4: Gate Charge test Circuit



# **TO-220 MECHANICAL DATA**

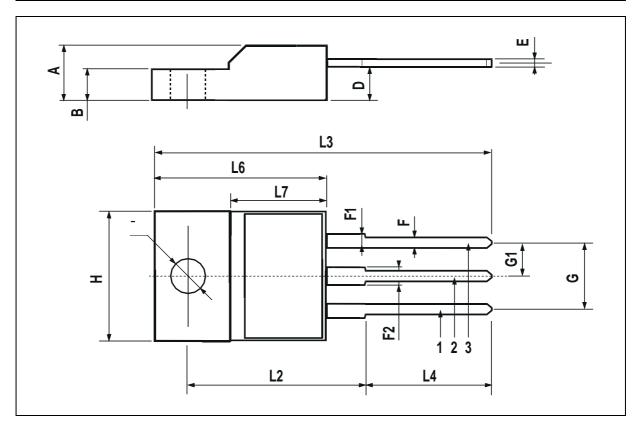
DIM.		mm			inch	
DIN.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	4.40		4.60	0.173		0.181
С	1.23		1.32	0.048		0.051
D	2.40		2.72	0.094		0.107
D1		1.27			0.050	
Е	0.49		0.70	0.019		0.027
F	0.61		0.88	0.024		0.034
F1	1.14		1.70	0.044		0.067
F2	1.14		1.70	0.044		0.067
G	4.95		5.15	0.194		0.203
G1	2.4		2.7	0.094		0.106
H2	10.0		10.40	0.393		0.409
L2		16.4			0.645	
L4	13.0		14.0	0.511		0.551
L5	2.65		2.95	0.104		0.116
L6	15.25		15.75	0.600		0.620
L7	6.2		6.6	0.244		0.260
L9	3.5		3.93	0.137		0.154
DIA.	3.75		3.85	0.147		0.151



**47/** 7/9

# **TO-220FP MECHANICAL DATA**

DIM.		mm			inch	
DINI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
Α	4.4		4.6	0.173		0.181
В	2.5		2.7	0.098		0.106
D	2.5		2.75	0.098		0.108
Е	0.45		0.7	0.017		0.027
F	0.75		1	0.030		0.039
F1	1.15		1.7	0.045		0.067
F2	1.15		1.7	0.045		0.067
G	4.95		5.2	0.195		0.204
G1	2.4		2.7	0.094		0.106
Н	10		10.4	0.393		0.409
L2		16			0.630	
L3	28.6		30.6	1.126		1.204
L4	9.8		10.6	0.385		0.417
L6	15.9		16.4	0.626		0.645
L7	9		9.3	0.354		0.366
Ø	3		3.2	0.118		0.126



Information furnished is believed to be accurate and reliable. However, STMicroelectronics assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of STMicroelectronics. Specification mentioned in this publication are subject to change without notice. This publication supersedes and replaces all information previously supplied. STMicroelectronics products are not authorized for use as critical components in life support devices or systems without express written approval of STMicroelectronics.

The ST logo is a trademark of STMicroelectronics

© 1999 STMicroelectronics – Printed in Italy – All Rights Reserved STMicroelectronics GROUP OF COMPANIES

Australia - Brazil - China - Finland - France - Germany - Hong Kong - India - Italy - Japan - Malaysia - Malta - Morocco - Singapore - Spain - Sweden - Switzerland - United Kingdom - U.S.A.

http://www.st.com

4